

# Octal Sample-and-Hold with Multiplexed Input

**SMP-18** 

## **FEATURES**

High Speed Version of SMP-08 Internal Hold Capacitors Low Droop Rate TTL/CMOS Compatible Logic Inputs Single or Dual Supply Operation Break-Before-Make Channel Addressing Compatible With CD4051 Pinout Low Cost

### **APPLICATIONS**

Multiple Path Timing Deskew for A.T.E. Memory Programmers
Mass Flow/Process Control Systems
Multichannel Data Acquisition Systems
Robotics and Control Systems
Medical and Analytical Instrumentation
Event Analysis
Stage Lighting Control

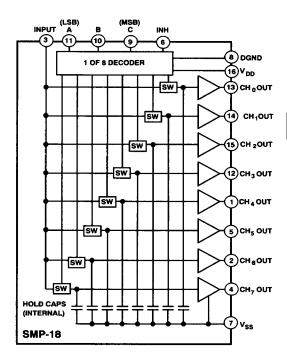
## GENERAL DESCRIPTION

The SMP-18 is a monolithic octal sample-and-hold; it has eight internal buffer amplifiers, input multiplexer, and internal hold capacitors. It is manufactured in an advanced oxide isolated CMOS technology to obtain high accuracy, low droop rate, and fast acquisition time. The SMP-18 has a typical linearity error of only 0.01% and can accurately acquire a 10-bit input signal to  $\pm 1/2$  LSB in less than 2.5 microseconds. The SMP-18's output swing includes the negative supply in both single and dual supply operation.

The SMP-18 was specifically designed for systems that use a calibration cycle to adjust a multiple of system parameters. The low cost and high level of integration make the SMP-18 ideal for calibration requirements that have previously required an ASIC, or high cost multiple D/A converters.

The SMP-18 is also ideally suited for a wide variety of sampleand-hold applications including amplifier offset or VCA gain adjustments. One or more SMP-18s can be used with single or multiple DACs to provide multiple set points within a system.

## FUNCTIONAL BLOCK DIAGRAM



The SMP-18 offers significant cost and size reduction over discrete designs. It is available in a 16-pin hermetic or plastic DIP or surface mount SOIC package. The SMP-18 is a higher speed direct replacement for the SMP-08.

## **SMP-18 SPECIFICATIONS**

## **ELECTRICAL CHARACTERISTICS** (@ $V_{DD}=+5$ V, $V_{SS}=-5$ V, DGND = 0 V, $R_L=$ No Load, $T_A=-40^{\circ}$ C to $+85^{\circ}$ C for SMP-18F, unless otherwise noted)

Parameter	Symbol	Conditions	Min	Тур	Max	Units
Linearity Error		$-3 \text{ V} \leq \text{V}_{\text{IN}} \leq +3 \text{ V}$		0.01		%
Buffer Offset Voltage	Vos	$T_A = +25^{\circ}C, V_{IN} = 0 \text{ V}$		2.5	10	mV
	00	$-40^{\circ}\text{C} \le \text{T}_{A} \le +85^{\circ}\text{C}, \text{V}_{IN} = 0 \text{ V}$		3.5	20	mV
Hold Step	V <sub>HS</sub>	$V_{IN} = 0 V$		4	6	mV
Droop Rate	$\Delta V_{CH}/\Delta t$	$T_A = +25^{\circ}C, V_{IN} = 0 \text{ V}$	ļ	2	40	mV/s
Output Source Current	I <sub>SOURCE</sub>	$V_{IN} = 0 V^{I}$	1.2			mA
Output Sink Current	I <sub>SINK</sub>	$V_{IN} = 0 V^1$	0.5			mA
Output Voltage Range		$R_L = 20 \text{ k}\Omega$	-3.0	ł	+3.0	V
LOGIC CHARACTERISTICS						
Logic Input High Voltage	V <sub>INH</sub>		2.4			V
Logic Input Low Voltage	VINL				0.8	V
Logic Input Current	I <sub>IN</sub>	$V_{IN} = 2.4 V$		0.5	1	μA
DYNAMIC PERFORMANCE <sup>2</sup>						
Acquisition Time	t <sub>AO</sub>	$T_A = +25^{\circ}C, -3 \text{ V to } +3 \text{ V to } 0.1\%$		3.5		μs
Hold Mode Settling Time	t <sub>H</sub>	To ±1 mV of Final Value	•	1		μs
Channel Select Time	t <sub>CH</sub>		ŀ	90		ns
Channel Deselect Time	t <sub>DCS</sub>			45		ns
Inhibit Recovery Time	t <sub>IR</sub>			90		ns
Slew Rate	SR			6	1	V/µs
Capacitive Load Stability		<30% Overshoot		500		pF
Analog Crosstalk		-3 V to +3 V Step		-72		dB
SUPPLY CHARACTERISTICS						
Power Supply Rejection Ratio	PSRR	$V_{SS} = \pm 5 \text{ V to } \pm 6 \text{ V}$	60	75		dB
Supply Current	$I_{DD}$	$T_A = +25^{\circ}C$		5.5	7.5	mA
		$-40^{\circ}\mathrm{C} \leq \mathrm{T_A} \leq +85^{\circ}\mathrm{C}$		7.5	9.5	mA

### NOTES

## **ELECTRICAL CHARACTERISTICS** (@ $V_{00} = +12$ V, $V_{SS} = 0$ V, DGND = 0 V, $R_L = No$ Load, $T_A = -40$ °C to +85°C for SMP-18F, unless otherwise noted)

Parameter	Symbol	Conditions	Min	Тур	Max	Units
Linearity Error Buffer Offset Voltage	Vos	60 mV $\leq$ V <sub>IN</sub> $\leq$ 10 V T <sub>A</sub> = +25°C, V <sub>IN</sub> = 6 V -40°C $\leq$ T <sub>A</sub> $\leq$ +85°C, V <sub>IN</sub> = 6 V		0.01 2.5 3.5	10 20	% mV mV
Hold Step Droop Rate Output Source Current Output Sink Current Output Voltage Range	V <sub>HS</sub> $\Delta V_{CH}/\Delta t$ $I_{SOURCE}$ $I_{SINK}$	$V_{IN} = 6 V$ $T_{A} = +25^{\circ}C, V_{IN} = 6 V$ $V_{IN} = 6 V^{1}$ $V_{IN} = 6 V^{1}$ $R_{L} = 20 k\Omega$ $R_{L} = 10 k\Omega$	1.2 0.5 0.06 0.06	4 2	6 40 10.0 9.5	mV mV/s mA mA V
LOGIC CHARACTERISTICS Logic Input High Voltage Logic Input Low Voltage Logic Input Current	V <sub>INH</sub> V <sub>INL</sub> I <sub>IN</sub>	V <sub>IN</sub> = 2.4 V	2.4	0.5	0.8 1	V V µA
DYNAMIC PERFORMANCE <sup>2</sup> Acquisition Time Hold Mode Settling Time Channel Select Time Channel Deselect Time Inhibit Recovery Time Slew Rate <sup>3</sup> Capacitive Load Stability Analog Crosstalk	t <sub>AQ</sub> t <sub>H</sub> t <sub>CH</sub> t <sub>DCS</sub> t <sub>IR</sub> SR	$T_A = +25^{\circ}\text{C}$ , 0 to 10 V to 0.1% To $\pm 1$ mV of Final Value		2.5 1 90 45 90 7 500 -72		μs μs ns ns v/μs pF dB

<sup>&</sup>lt;sup>1</sup>Outputs are capable of sinking and sourcing over 10 mA but offset is guaranteed at specified load levels.

<sup>&</sup>lt;sup>2</sup>All input control signals are specified with  $t_r = t_f = 5$  ns (10% to 90% of +5 V) and timed from a voltage level of 1.6 V.

Specifications subject to change without notice.

Parameter	Symbol	Conditions	Min	Тур	Max	Units
SUPPLY CHARACTERISTICS Power Supply Rejection Ratio Supply Current	PSRR I <sub>DD</sub>	$10.8 \text{ V} \le \text{V}_{\text{DD}} \le 13.2 \text{ V}$ $\text{T}_{\text{A}} = +25^{\circ}\text{C}$ $-40^{\circ}\text{C} \le \text{T}_{\text{A}} \le +85^{\circ}\text{C}$	60	75 6.0 8.0	8.0 10.0	dB mA mA

### NOTES

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Outputs are capable of sinking and sourcing over 10 mA but offset is guaranteed at specified load levels.

<sup>2</sup>All input control signals are specified with  $t_r = t_f = 5$  ns (10% to 90% of +5 V) and timed from a voltage level of 1.6 V.

0.237 1737

<sup>3</sup>Slew rate is measured in the sample mode with a 0 to 10 V step from 20% to 80%.

Specifications subject to change without notice.

## ABSOLUTE MAXIMUM RATINGS<sup>1</sup>

Storage Temperature . . . . . . . . . . . . -65°C to +150°C Lead Temperature (Soldering, 60 sec) .....+300°C

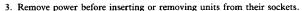
Package Type	$\theta_{JA}^2$	θ <sub>JC</sub>	Units
16-Pin Hermetic DIP (Q)	94	12	°C/W
16-Pin Plastic DIP (P)	76	33	°C/W
16-Pin SOIC (S)	92	27	°C/W

### NOTES

- 1. Absolute maximum ratings apply to both DICE and packaged parts, unless otherwise noted.
- 2.  $\theta_{JA}$  is specified for worst case mounting conditions, i.e.,  $\theta_{JA}$  is specified for device in socket for cerdip and plastic DIP packages;  $\theta_{JA}$  is specified for device soldered to printed circuit board for SOIC package.

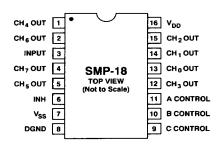
## CAUTION

- 1. Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied. Exposure to the above maximum rating conditions for extended periods may affect device reliability.
- 2. Digital inputs and outputs are protected; however, permanent damage may occur on unprotected units from high-energy electrostatic fields. Keep units in conductive foam or packaging at all times until ready to use. Use proper antistatic handling procedures.





## PIN CONNECTIONS



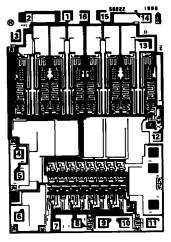
## **ORDERING GUIDE\***

Package: 16-1	Pin DIP/SOIC	DIP/SOIC Operating		
Cerdip 16-Pin	Plastic 16-Pin	Temperature Range		
TBA† SMP-18FQ	SMP-18FP SMP-18FS	MIL XIND XIND		

\*Burn-in is available on industrial temperature range parts in cerdip and plastic DIP packages.

†Consult factory for 883 data sheet.

## DICE CHARACTERISTICS



DIE SIZE 0.080 x 0.120 INCH, 9,600 sq. mils (2.032 x 3.048 mm, 6.193 sq. mm)

1.	CH <sub>4</sub> OUT	9. C CONTRO	L
2.	CH <sub>6</sub> OUT	10. B CONTRO	Ł
3.	INPUT	11. A CONTRO	Ł
4.	CH <sub>7</sub> OUT	12. CH <sub>3</sub> OUT	
5.	CH <sub>5</sub> OUT	13. CH <sub>O</sub> OUT	
6.	INH	14. CH <sub>1</sub> OUT	
7.	v <sub>ss</sub>	15. CH <sub>2</sub> OUT	
8.	DGND	16. V <sub>DD</sub>	

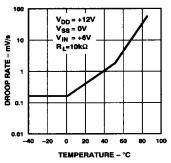
## WAFER TEST LIMITS (@ $V_{DD}=+12$ V, $V_{SS}=$ DGND = 0 V, $R_L=$ No Load, $T_A=+25^{\circ}$ C for SMP-18GBC, unless otherwise specified)

Parameter	Symbol	Conditions	Limits	Units	
Buffer Offset Voltage Droop Rate Output Source Current Output Sink Current Output Voltage Range	V <sub>OS</sub> $\Delta V_{CH}/\Delta t$ I SOURCE I SINK	$V_{IN} = +6 V V_{IN} = +6 V V_{IN} = +6 V V_{IN} = +6 V R_{L} = 20 k\Omega R_{L} = 10 k\Omega$	20 40 1.2 0.5 0.06/10.0 0.06/9.5	mV max mV/s max mA min mA min V max/min V max/min	
LOGIC CHARACTERISTICS Logic Input High Voltage Logic Input Low Voltage Logic Input Current	V <sub>INH</sub> V <sub>INL</sub> I <sub>IN</sub>	V <sub>IN</sub> = 2.4 V	2.4 0.8 1	V min V max μA max	
SUPPLY CHARACTERISTICS Power Supply Rejection Ratio Supply Current	PSRR I <sub>DD</sub>	$10.8 \text{ V} \le \text{V}_{\text{DD}} \le 13.2$	60 8.0	dB min mA max	

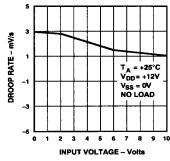
NOTE

Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualifications through sample lot assembly and testing.

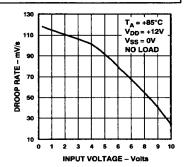
## **Typical Performance Characteristics—SMP-18**



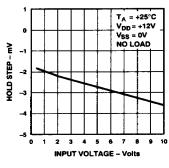
Droop Rate vs. Temperature



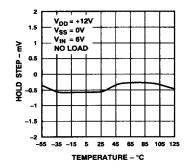
Droop Rate vs. Input Voltage



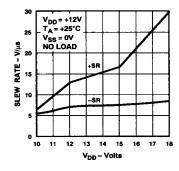
Droop Rate vs. Input Voltage



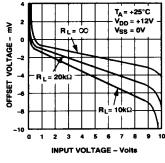
Hold Step vs. Input Voltage



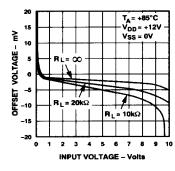
Hold Step vs. Temperature



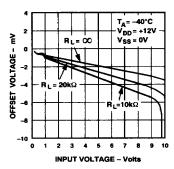
Slew Rate vs. V<sub>DD</sub>



Offset Voltage vs. Input Voltage

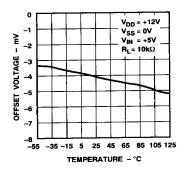


Offset Voltage vs. Input Voltage

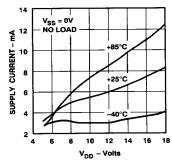


Offset Voltage vs. Input Voltage

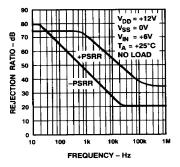
## SMP-18—Typical Performance Characteristics



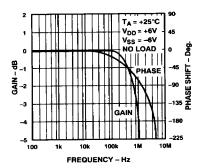
Offset Voltage vs. Temperature



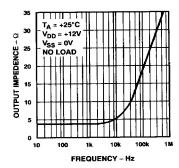
Supply Current vs. VDD



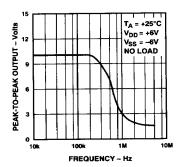
Sample Mode Power Supply Rejection



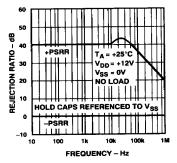
Gain, Phase Shift vs. Frequency



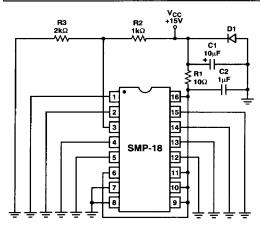
Output Impedance vs. Frequency



Maximum Output Voltage vs. Frequency



Hold Mode Power Supply Rejection



Burn-in Circuit

## APPLICATIONS INFORMATION

The SMP-18, a multiplexed octal S/H, minimizes board space in systems requiring cycled calibration or an array of control voltages. When used in conjunction with a low cost 10-bit D/A, the SMP-18 can easily be integrated into microprocessor based systems. Since the SMP-18 features break-before-make switching and an internal decoder, no external logic is required. The SMP-18 has an internally regulated TTL supply so that TTL/CMOS compatibility is maintained over the full supply range. See Figure 1 for channel decode address information.

## **POWER SUPPLIES**

The SMP-18 is capable of operating with either single or dual supplies, over a voltage range of 7 to 15 volts. Based on the supply voltages chosen,  $V_{\rm DD}$  and  $V_{\rm SS}$  establish the output voltage range, which is:

$$(V_{SS} + \theta.06~V) \leq V_{OUT} \leq (V_{DD} - 2~V)$$

Note that several specifications, including acquisition time, offset and output voltage, compliance will degrade for supply voltages of less than 7 V.

If split supplies are used, the negative supply should be bypassed with a  $0.1~\mu F$  capacitor in parallel with a  $10~\mu F$  to ground. The internal hold capacitors are connected to this supply pin and any noise will appear at the outputs.

In single supply applications, it is extremely important that the  $V_{SS}$  (negative supply) pin is connected to a clean ground. The hold capacitors are internally tied to the  $V_{SS}$  (negative) rail. Any ground noise or disturbance will directly couple to the output of the sample-and-hold, degrading the signal-to-noise performance. The analog and digital ground traces on the circuit board should be physically separated to reduce digital switching noise from entering the analog circuitry.

## POWER SUPPLY SEQUENCING

 ${
m V_{DD}}$  should be applied to the SMP-18 before the logic input signals. The SMP-18 has been designed to be immune to latchup, but standard precautions should still be taken.

## OUTPUT BUFFERS (Pins 1, 2, 4, 5, 12, 13, 14, 15)

The buffer offset specification is 10 mV; this is less than 1/2 LSB of an 8-bit DAC with 10 V full scale. The hold step (magnitude of step caused in the output voltage when switching from sample-to-hold mode, also referred to as the pedestal error or sample-to-hold offset) is about 4 mV with little variation over the full output voltage range. The droop rate of a held channel is 2 mV/s typical and 40 mV/s maximum.

The buffers are designed to drive loads connected to ground. The outputs can source more than 20 mA, over the full voltage range, but have limited current sinking capability near  $V_{\rm SS}$ . In split supply operation, symmetrical output swings can be obtained by restricting the output range to 2 V from either supply.

On-chip SMP-18 buffers eliminate potential stability problems associated with external buffers; outputs are stable with capacitive loads up to 500 pF. However, since the SMP-18's buffer outputs are not short circuit protected, care should be taken to avoid shorting any output to the supplies or ground.

## SIGNAL INPUT (Pin 3)

The signal input should be driven from a low impedance voltage source such as the output of an op amp. The op amp should have a high slew rate and fast settling time if the SMP-18's acquisition time characteristics are to be maintained. As with all CMOS devices, all input voltages should be kept within range of the supply rails ( $V_{SS} \leq V_{IN} \leq V_{DD}$ ) to avoid the possibility of latch-up. If single supply operation is desired, op amps such as the OP-21, OP-80, or OP-90 that have input and output voltage compliances including ground, can be used to drive the inputs. Split supplies, such as  $\pm 7.5$  V, can be used with the SMP-18.

## APPLICATION TIPS

All unused digital inputs should be connected to logic LOW. For analog inputs that may become temporarily disconnected, a resistor to  $V_{\rm DD},\,V_{\rm SS}$  or analog ground should be used with a value ranging from 200 k $\Omega$  to 1  $M\Omega.$ 

Do not apply signals to the SMP-18 with power off unless the input current is limited to less than 10 mA.

## TYPICAL APPLICATIONS

## An 8-Channel Multiplexed D/A Converter

Figure 1 illustrates a typical multiplexing function of the SMP-18. It is used to sample-and-hold eight different output voltages corresponding to eight different digital codes from a D/A converter. The SMP-18's droop rate of 40 mV/s requires a refresh

once every 250 ms before the voltage drifts beyond 1/2 LSB accuracy (1 LSB of an 8-bit DAC is equivalent to 19.5 mV, out of a full-scale voltage of 5 V). For a 10-bit DAC, the refresh rate must be less than 60 ms, and for a 12-bit system, 15 ms. This implementation is very cost effective compared to using multiple DACs as the number of output channels increases.

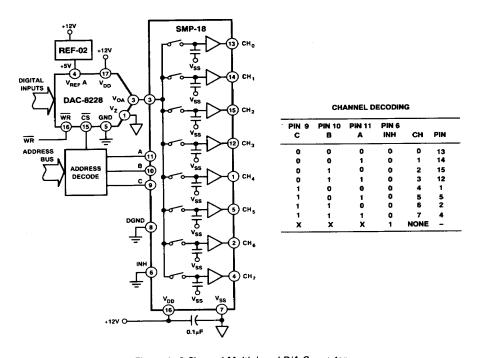


Figure 1. 8-Channel Multiplexed D/A Converter